

## **Advanced characterization of electrowetting retroreflectors**

Kilaru MK, Yang J, Heikenfeld J.

Optics express

2009; 17(20):17563-17569

### **ARTICLE IDENTIFIERS**

DOI: unavailable

PMID: 19907540

PMCID: not available

### **JOURNAL IDENTIFIERS**

LCCN: sn 97000184

pISSN: not available

eISSN: 1094-4087

OCLC ID: 37160672

CONS ID: not available

US National Library of Medicine ID: 101137103

This article was identified from a query of the SafetyLit database.